


<b>Search Notes</b>  	<b>Application/Control No.</b>  10717607	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  Keefer, Michael E	<b>Art Unit</b>  2454

SEARCHED			
Class	Subclass	Date	Examiner
709	227 (updated 12/5/2008)	7/13/2007	MEK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	7/13/2007	MEK
Consulted Examiner Hassan Phillips	7/12/2007	MEK
Consulted Examiner Dustin Nguyen	7/12/2007	MEK
Consulted Examiner Hassan Phillips, class 709	12/2/2008	MEK
Consulted Primary Examiner Dustin Nguyen, class 709	12/5/2008	MEK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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